

International
IR Rectifier
POWER MOSFET
THRU-HOLE (TO-257AA)

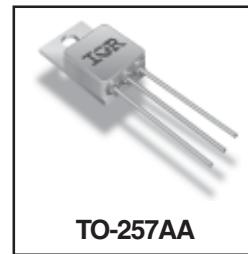
PD - 94197C

IRFY9140, IRFY9140M
100V, P-CHANNEL
HEXFET® MOSFET TECHNOLOGY

Product Summary

Part Number	RDS(on)	ID	Eyelets
IRFY9140	0.20 Ω	-15.8A	Glass
IRFY9140M	0.20 Ω	-15.8A	Glass

HEXFET® MOSFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance. HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required. The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.



TO-257AA

Features:

- Simple Drive Requirements
 - Ease of Parallelizing
 - Hermetically Sealed
 - Electrically Isolated
 - Glass Eyelets
 - For Space Level Applications
- Refer to Ceramic Version Part Numbers IRFY9140C, IRFY9140CM

Absolute Maximum Ratings

	Parameter		Units
ID @ VGS = -10V, TC = 25°C	Continuous Drain Current	-15.8	A
ID @ VGS = -10V, TC = 100°C	Continuous Drain Current	-10	
IDM	Pulsed Drain Current ①	-60	W
PD @ TC = 25°C	Max. Power Dissipation	100	
	Linear Derating Factor	0.8	W/C
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ②	640	mJ
IAR	Avalanche Current ①	-15.8	A
EAR	Repetitive Avalanche Energy ①	10	mJ
dv/dt	Peak Diode Recovery dv/dt ③	-5.5	V/ns
T _J	Operating Junction	-55 to 150	°C
T _{STG}	Storage Temperature Range		
	Lead Temperature	300(0.063in./1.6mm from case for 10 sec)	
	Weight	4.3 (Typical)	g

For footnotes refer to the last page

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (Unless Otherwise Specified)

	Parameter	Min	Typ	Max	Units	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-100	—	—	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_D = -1.0\text{mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Temperature Coefficient of Breakdown Voltage	—	-0.1	—	$\text{V}/^\circ\text{C}$	Reference to 25°C , $\text{I}_D = -1.0\text{mA}$
$\text{R}_{\text{DS(on)}}$	Static Drain-to-Source On-State Resistance	—	—	0.20	Ω	$\text{V}_{\text{GS}} = -10\text{V}, \text{I}_D = -10\text{A}$ ④
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	-2.0	—	-4.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{I}_D = -250\mu\text{A}$
g_{fs}	Forward Transconductance	6.2	—	—	S (Ω)	$\text{V}_{\text{DS}} > -15\text{V}, \text{I}_{\text{DS}} = -10\text{A}$ ④
I_{DSS}	Zero Gate Voltage Drain Current	—	—	-25	μA	$\text{V}_{\text{DS}} = -80\text{V}, \text{V}_{\text{GS}} = 0\text{V}$
		—	—	-250		$\text{V}_{\text{DS}} = -80\text{V}, \text{V}_{\text{GS}} = 0\text{V}, \text{T}_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Leakage Forward	—	—	-100	nA	$\text{V}_{\text{GS}} = -20\text{V}$
I_{GSS}	Gate-to-Source Leakage Reverse	—	—	100		$\text{V}_{\text{GS}} = 20\text{V}$
Q_g	Total Gate Charge	—	—	60	nC	$\text{V}_{\text{GS}} = -10\text{V}, \text{I}_D = -15.8\text{A}$
Q_{gs}	Gate-to-Source Charge	—	—	13		$\text{V}_{\text{DS}} = -50\text{V}$
Q_{gd}	Gate-to-Drain ('Miller') Charge	—	—	35.2		
$t_{\text{d(on)}}$	Turn-On Delay Time	—	—	35	ns	$\text{V}_{\text{DD}} = -50\text{V}, \text{I}_D = -15.8\text{A}, \text{V}_{\text{GS}} = -10\text{V}, \text{R}_G = 7.5\Omega$
t_r	Rise Time	—	—	85		
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	—	85		
t_f	Fall Time	—	—	65		
$\text{L}_{\text{S}} + \text{L}_{\text{D}}$	Total Inductance	—	6.8	—	nH	Measured from drain lead (6mm/0.25in. from package) to source lead (6mm/0.25in. from package)
C_{iss}	Input Capacitance	—	1400	—	pF	$\text{V}_{\text{GS}} = 0\text{V}, \text{V}_{\text{DS}} = -25\text{V}$ $f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	600	—		
C_{rss}	Reverse Transfer Capacitance	—	200	—		

Source-Drain Diode Ratings and Characteristics

	Parameter	Min	Typ	Max	Units	Test Conditions
I_{S}	Continuous Source Current (Body Diode)	—	—	-15.8	A	
I_{SM}	Pulse Source Current (Body Diode) ①	—	—	-60		
V_{SD}	Diode Forward Voltage	—	—	-5.0	V	$\text{T}_J = 25^\circ\text{C}, \text{I}_{\text{S}} = -15.8\text{A}, \text{V}_{\text{GS}} = 0\text{V}$ ④
t_{rr}	Reverse Recovery Time	—	—	280	nS	$\text{T}_J = 25^\circ\text{C}, \text{I}_{\text{F}} = -15.8\text{A}, \text{di/dt} \leq -100\text{A}/\mu\text{s}$ $\text{V}_{\text{DD}} \leq -50\text{V}$ ④
Q_{RR}	Reverse Recovery Charge	—	—	3.6	μC	
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $\text{L}_{\text{S}} + \text{L}_{\text{D}}$.				

Thermal Resistance

	Parameter	Min	Typ	Max	Units	Test Conditions
R_{thJC}	Junction-to-Case	—	—	1.25	$^\circ\text{C/W}$	Typical socket mount
R_{thCS}	Case-to-sink	—	0.21	—		
R_{thJA}	Junction-to-Ambient	—	—	80		

Note: Corresponding Spice and Saber models are available on International Rectifier Website.

For footnotes refer to the last page

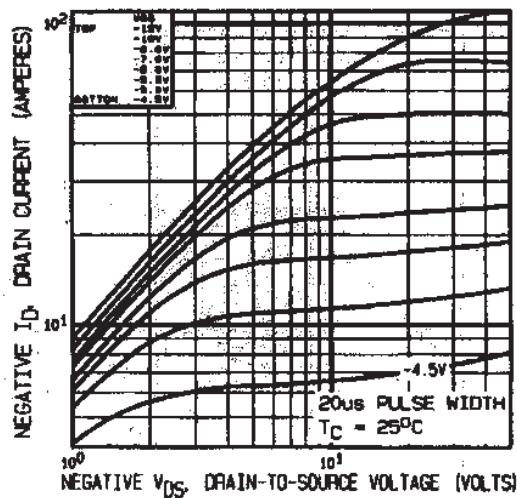


Fig 1. Typical Output Characteristics

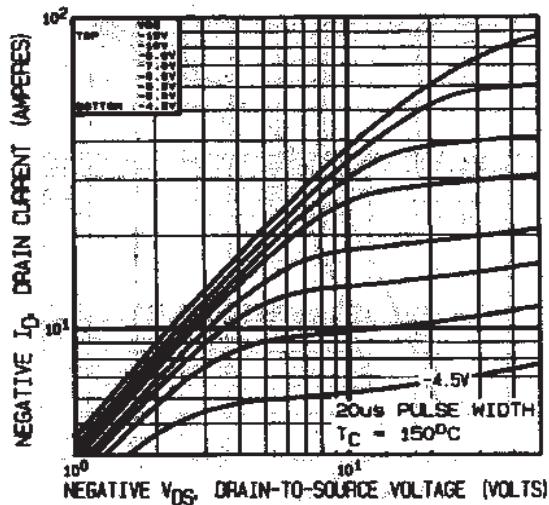


Fig 2. Typical Output Characteristics

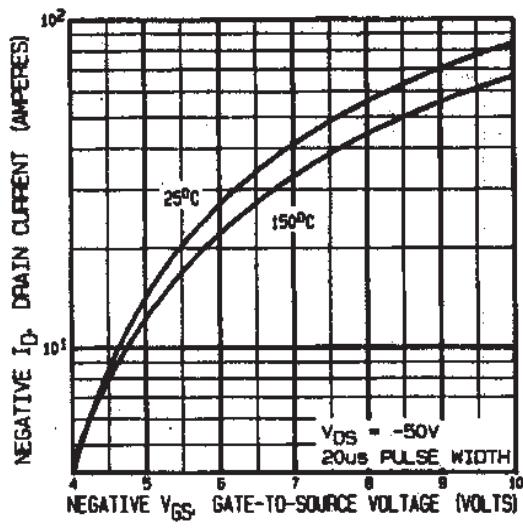


Fig 3. Typical Transfer Characteristics

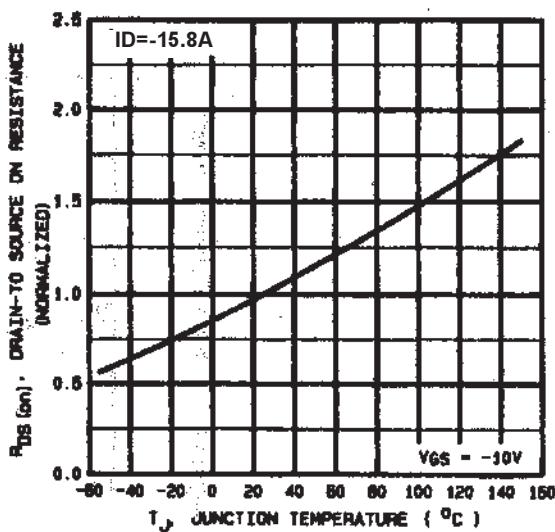


Fig 4. Normalized On-Resistance
 Vs. Temperature

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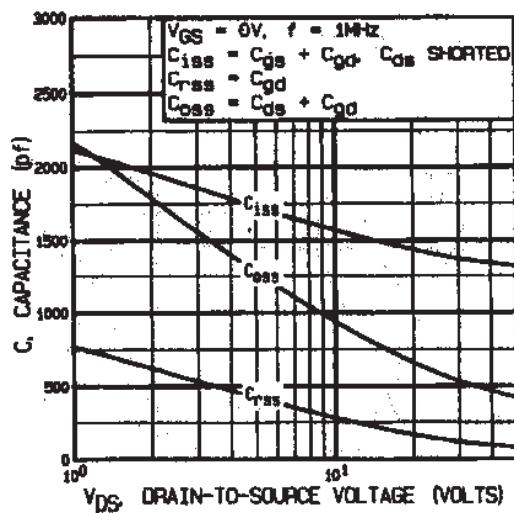


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

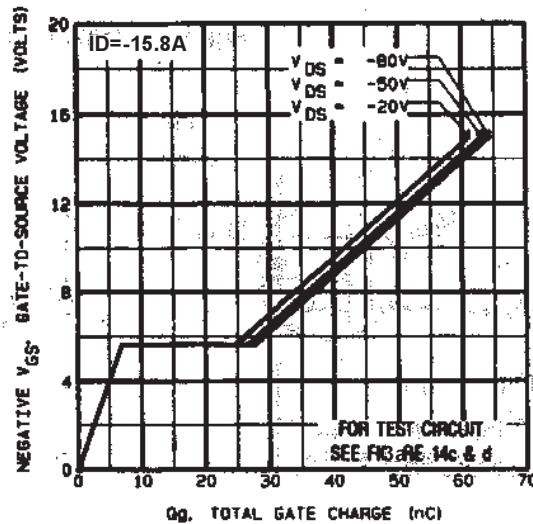


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

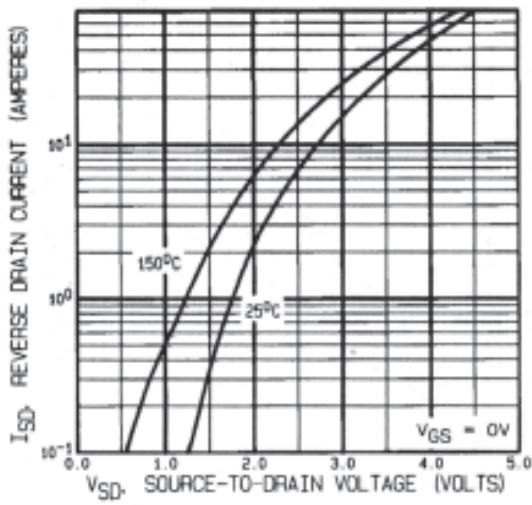


Fig 7. Typical Source-Drain Diode
Forward Voltage

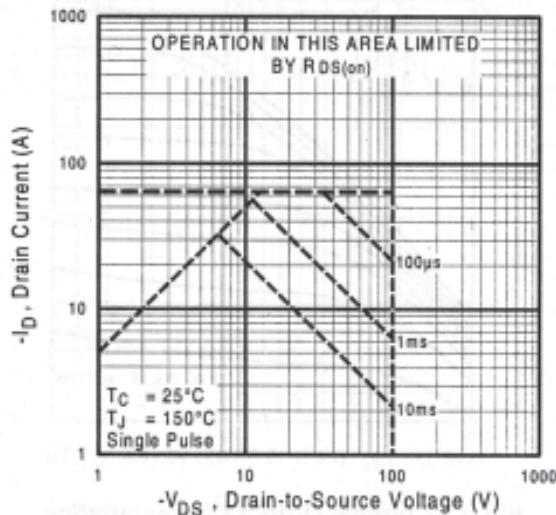


Fig 8. Maximum Safe Operating Area

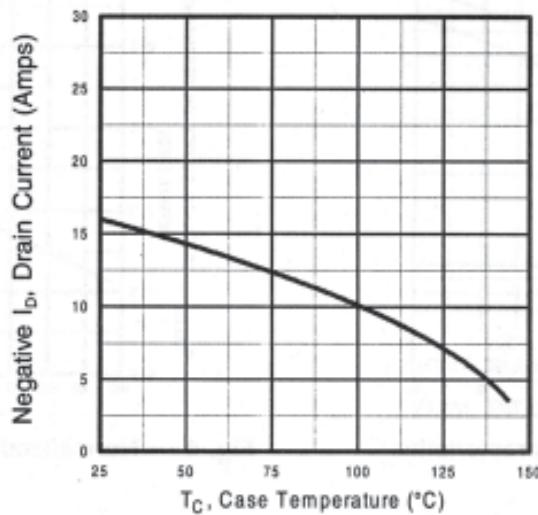


Fig 9. Maximum Drain Current Vs.
Case Temperature

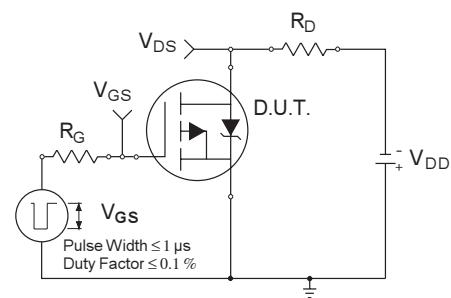


Fig 10a. Switching Time Test Circuit

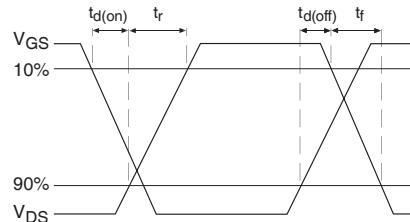


Fig 10b. Switching Time Waveforms

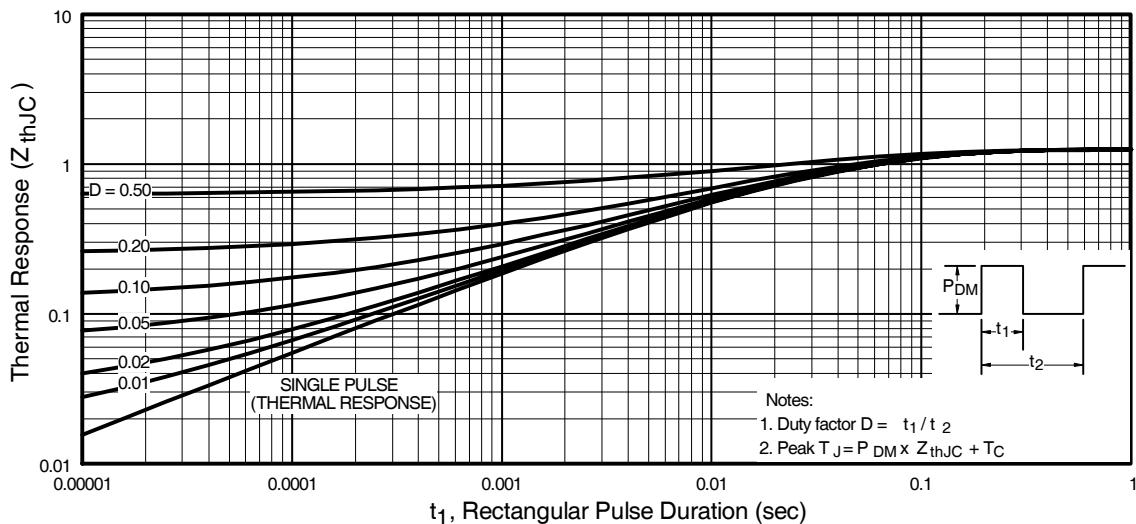


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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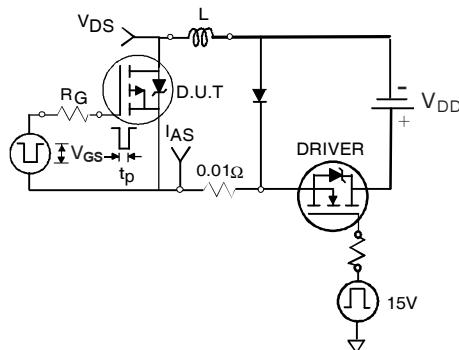


Fig 12a. Unclamped Inductive Test Circuit

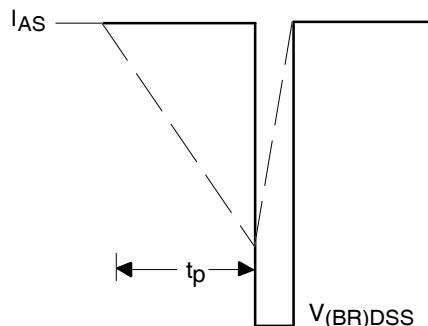
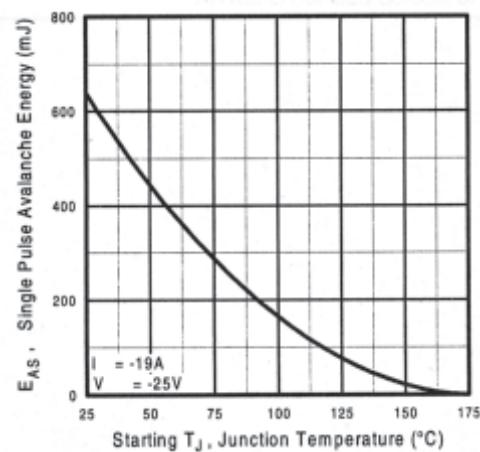


Fig 12b. Unclamped Inductive Waveforms

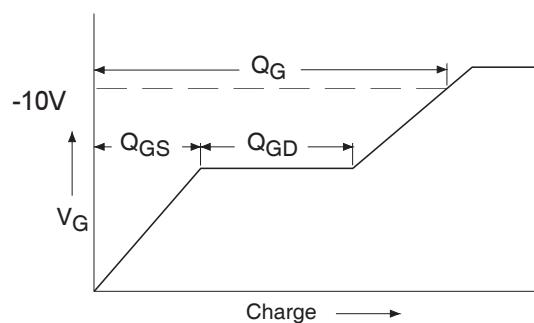


Fig 13a. Basic Gate Charge Waveform

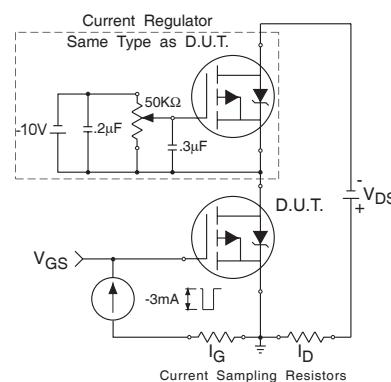


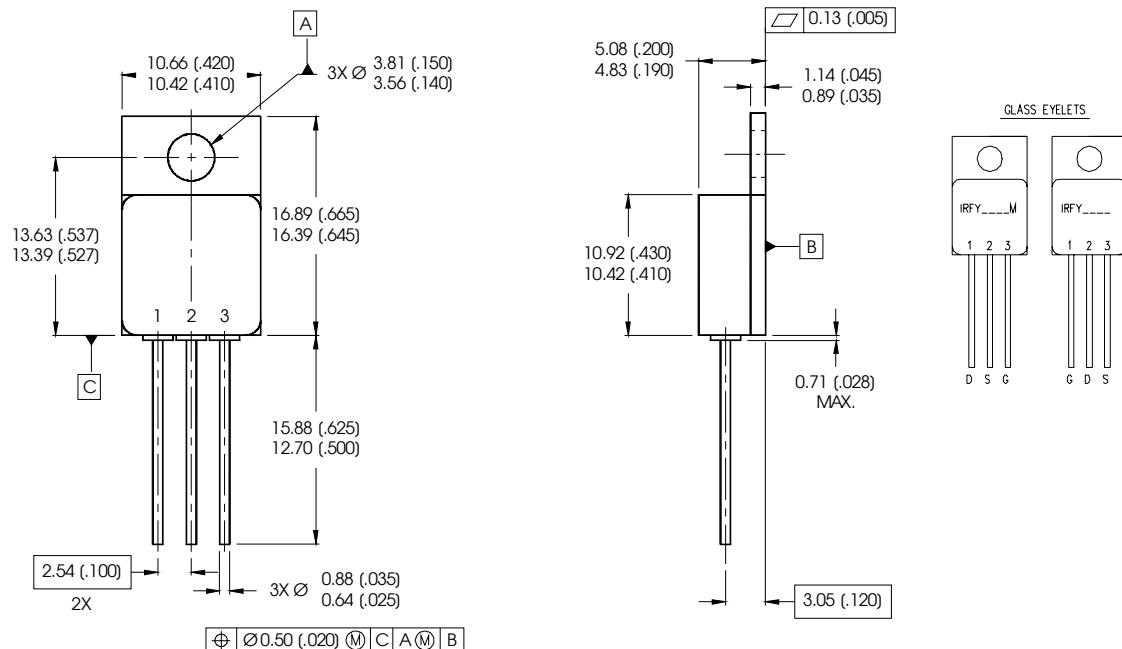
Fig 13b. Gate Charge Test Circuit

Foot Notes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② V_{DD} = -50V, starting T_J = 25°C, L = 5.1mH Peak I_L = -15.8A, V_{GS} = -10V

- ③ I_{SD} ≤ -15.8A, di/dt ≤ -200A/μs, V_{DD} ≤ -100V, T_J ≤ 150°C
- ④ Pulse width ≤ 300 μs; Duty Cycle ≤ 2%

Case Outline and Dimensions — TO-257AA



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Data and specifications subject to change without notice. 01/2007